

<b>Notice of References Cited</b>	Application/Control No. 10/078,074	Applicant(s)/Patent Under Reexamination CHUNG, SEUK HWAN	
	Examiner Phylesha L. Dabney	Art Unit 2646	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,208,237	03-2001	Saiki et al.	340/388.1
*	B	US-6,560,347	05-2003	Chung, Seuk Hwan	381/420
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

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